

SANYO Semiconductors

DATA SHEET

An ON Semiconductor Company

CMOSIC

LC72725KMA — RDS(RBDS) Demodulation IC

Overview

The LC72725KMA is IC that implement the signal processing required by the European Broadcasting Union RDS (Radio Data System) standard and by the US NRSC (National Radio System Committee) RBDS (Radio Broadcast Data System) standard. This IC include band-pass filter, demodulator, and data buffer on chip. RDS data can be read out from this on-chip memory by external clock input in slave operation mode.

Functions

- Bandpass filter: Switched capacitor filter (SCF)
- RDS Demodulation: 57kHz carrier and RDS data clock regeneration, biphase decode, differential decode.
- Buffer: 128 bit (about 100ms) can be restored in the on-chip data buffer RAM.
- Data output: Master or slave output mode can be selected.
- RDS-ID: Detect RDS signal which can be reset by RST signal input.
- Standby control: Crystal oscillator can be stopped.
- Fully adjustment free
- Low Voltage

Specifications

Absolute Maximum Ratings at Ta = 25°C, $V_{SS}d = V_{SS}a = 0V$

Parameter	Symbol	Pin Name	Conditions	Ratings	Unit
Maximum supply voltage	V _{DD} max	V _{DD} d, V _{DD} a *	V _{DD} a≤V _{DD} d+0.3V	-0.3 to +6.5	V
Maximum input voltage	V _{IN} 1 max	TEST, MODE, XIN, RDCL, RST		-0.3 to V _{DD} d+0.3	V
	V _{IN} 2 max	MPXIN, CIN		-0.3 to V _{DD} a+0.3	V
Maximum output voltage	V _O 1 max	RDS-ID(READY)		-0.3 to +6.5	V
	V _O 2 max	XOUT, RDDA, RDCL		-0.3 to V _{DD} d+0.3	V
	V _O 3 max	FLOUT		-0.3 to V _{DD} a+0.3	V
Maximum output current	I _O 1 max	XOUT, FLOUT, RDDA, RDCL		+2.0	mA
	I _O 2 max	RDS-ID(READY)		+8.0	mA

^{*} VDDa≤VDDd+0.3V

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Parameter	Symbol	Pin Name	Conditions	Ratings	Unit
Allowable power dissipation	Pd max		Ta≤85°C	140	mW
Operating temperature	Topr1		V _{DD} = 2.7V to 5.5V	-20 to +70	°C
	Topr2		V _{DD} = 3.0V to 5.5V	-40 to +85	°C
Storage temperature	Tstg			-40 to +125	°C

$\label{eq:lowable Operating Ranges} \begin{array}{l} \text{Allowable Operating Ranges} \ at \ Ta = -20 \ to \ +70 ^{\circ}\text{C}, \ V_{SS}d = V_{SS}a = 0\text{V}, \ V_{DD}d = V_{DD}a = 2.7\text{V} \ to \ 5.5\text{V} \\ Ta = -40 \ to \ +85 ^{\circ}\text{C}, \ V_{SS}d = V_{SS}a = 0\text{V}, \ V_{DD}d = V_{DD}a = 3.0\text{V} \ to \ 5.5\text{V} \\ \end{array}$

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Parameter	Symbol	Pin Name	Conditions		Ratings			
i didilictoi	Symbol Fill Name	Pin Name		min	typ	max	unit	
Supply voltage	V _{DD} 1	V _{DD} d, V _{DD} a	Ta = -20 to +70°C	2.7		5.5		
	V_{DD}^2	V _{DD} d, V _{DD} a	Ta = -40 to +85°C	3.0		5.5	V	
Input high-level voltage	V _{IH} 1	TEST, MODE, RST		0.7V _{DD} d		6.5	V	
	V _{IH} 2	RDCL		0.7V _{DD} d		$V_{\mbox{\scriptsize DD}} d$	V	
Input low-level voltage	V _{IL}	TEST, MODE, RST, RDCL		0		0.3V _{DD} d	V	
Output voltage	V _O 1	RDDA, RDCL				$V_{DD}d$	V	
	V _O 2	RDS-ID(READY)				6.5	V	
Input amplitude	VIN	MPXIN	f = 57±2kHz	1.6		50	mVrms	
	VXIN	XIN		400		1500	mVrms	
Guaranteed crystal oscillator frequencies	Xtal	XIN, XOUT	Cl≤120Ω		4.332		MHz	
Crystal oscillator operating range	TXtal	XIN, XOUT	Fo = 4.332MHz			±100	ppm	
RDCL setup time	tCS	RDCL, RDDA		0			μS	
RDCL high-level time	tCH	RDCL		0.75			μS	
RDCL low-level time	tCL	RDCL		0.75			μS	
Data output time	tDC	RDCL, RDDA				0.75	μS	
READY output time	tRC	RDCL, READY				0.75	μS	
READY low-level time	tRL	READY			_	107	ms	

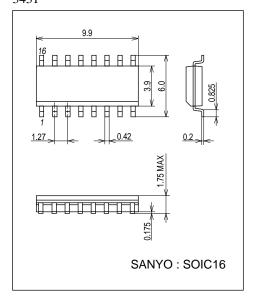
Electrical Characteristics for the Allowable Operating Ranges

B	0 1 1	D'a Nama	0 - 111		Ratings		
Parameter	Symbol	Pin Name	Conditions	min	typ	max	unit
Input resistance	Rmpxin	MPXIN-V _{SS} a	f = 57kHz		100		kΩ
	Rcin	CIN-V _{SS} a	f = 57kHz		100		kΩ
Internal feedback resistance	Rf	XIN			1.0		МΩ
Center frequency	fc	FLOUT		56.5	57.0	57.5	kHz
-3dB band width	BW-3dB	FLOUT		2.5	3.0	3.5	kHz
Gain	Gain	MPXIN-FLOUT	f = 57kHz	28	31	34	dB
Stop band attenuation	Att1	FLOUT	$\Delta f = \pm 7kHz$	30			dB
	Att2	FLOUT	F<45kHz, f>70kHz	40			dB
	Att3	FLOUT	F<20kHz	50			dB
Reference voltage output	Vref	Vref	V _{DD} a = 3V		1.5		V
Hysteresis	VHIS	TEST, MODE, RST, RDCL			0.1V _{DD} d		V
Output low-level voltage	V _{OL} 1	RDDA, RDCL	I = 2mA			0.4	V
	V _{OL} 2	RDS-ID(READY)	I = 8mA			0.4	V
Output high-level voltage	Voн	RDDA, RDCL	I = 2mA	V _{DD} d-0.4			V
Input high-level current	I _{IH} 1	TEST, MODE, RST, RDCL	V _I = 6.5V			5.0	μА
	I _{IH} 2	XIN	$V_I = V_{DD}d$	2.0		11	μА
Input low-level current	I _{IL} 1	TEST, MODE, RST, RDCL	V _I = 0V			5.0	μА
	I _{IL} 2	XIN	V _I = 0V	2.0		11	μА
Output off leakage current	IOFF	RDS-ID(READY)	V _O = 6.5V		_	5.0	μΑ
Current drain	I _{DD}	V _{DD} d+V _{DD} a	$V_{DD}d+V_{DD}a$ $(V_{DD}d = V_{DD}a = 3V)$		5		mA

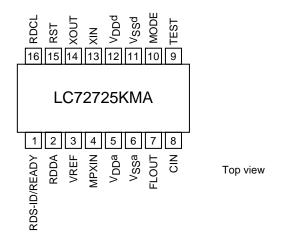
Package Dimensions

unit:mm (typ)

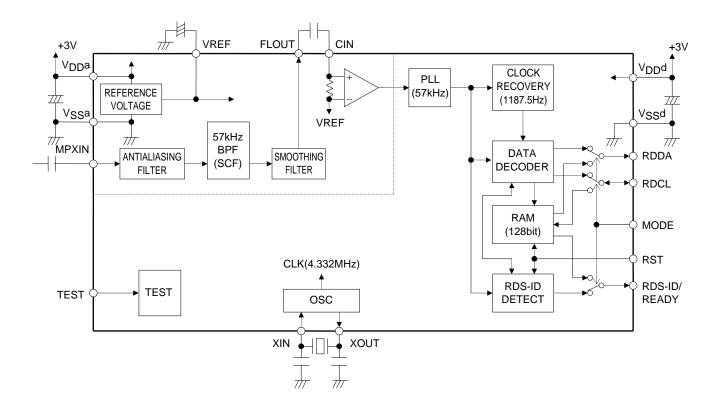
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Pin Assignment



Block Diagram



Pin Descriptions

Vision V	Pin Des	_		Function	Die Cirerit
4 MPXIN Input Baseband (multiplexed) signal input VDDd VSSd 7 FLOUT Output Subcarrier output (filter output) 8 CIN Input Subcarrier input (comparator input) 5 VDDd - Analog system power supply (+3V) 6 VSSa - Analog system power supply (+3V) 14 XOUT Output 13 XIN Input Congular output (4332MHz) Test input (comparator input) VDDd XXIN Input Congular output (4332MHz) Cystal oscillator input (external inference signal input) Test input Read out mode (0 master, 1 siave) RDS-IDRAM reset (active high) 7 VDDd XXIN Input (external inference signal input) Test input Read out mode (0 master, 1 siave) RDS-IDRAM reset (active high) 7 VDDd VSSd 16 RDCL I/O RDS data output RDS data output High case with right RDS reliability (false output (flave mode)) RDS reliability data output High case with RDR RDS reliability (READY output (active high)) RDS reliability (active high) 7 VSSd 7 VDDd	Pin No.	Pin Name	I/O	Function Reference veltage output (Video/2)	Pin Circuit
7 FLOUT Output Subcarrier output (filter output) 8 CIN Input Subcarrier input (comparator input) 5 Vppa - Analog system power supply (+3V) 6 Vssa - Analog system power supply (+3V) 14 XOUT Output Crystal oscillator output (4.332MHz) 17 Test input Read out mode (Comastar, 1:slave) 18 RDDA Output RDS data output 19 RDS-ID/RAM reset (active high) 10 RDS-ID/RAM reset (active high) 11 RDS-ID/ RDS read out clock input (slave mode) 12 Vppd - Output RDS reliability (ata output (4.94 Nor RDS reliability) READY output (active high) 10 RDS-ID/RAM reset (base mode) 11 RDS-ID/ RDS reliability data output (4.94 Nor RDS reliability) READY output (active high) 12 Vppd - Output RDS reliability (READY output (active high)	3	VREF	Output	Reference voltage output (Vada/2)	*
8 CIN Input Subcarrier input (comparator input) 5 VDDa - Analog system power supply (+3V) 6 VSSa - Analog system ground 14 XOUT Output Crystal oscillator output (4.332MHz) 13 XIN Input Crystal oscillator input (external reference signal input) 7 Test input Read out mode (0:master, 1:slave) 15 RST RDA Output RDS data output 16 RDCL I/O RDS clock output (master mode) / RDS read out clock input (slave mode) 1 RDS-ID/ RAM reset (active high) TOTAL COMPART (High:data with high RDS reliability Low: data with low RDS reliability Low	4	MPXIN	Input	Baseband (multiplexed) signal input	
5 VDDa - Analog system power supply (+3V) 6 VSSa - Analog system ground 14 XOUT Output Crystal oscillator output (4.332MHz) 13 XIN Input Crystal oscillator input (external reference signal input) - Test input Read out mode (0:master, 1:slave) RDS-ID/RAM reset (active high) - RDS data output - RDS data output - RDS data output - RDS data output (slave mode) - RDS relability (low: data with low RDS reliability) READY Output (active high) - RDS reliability (READY output (active high) - RDS reliability (READY output (active high) - RDS reliability) - READY output (active high)	7	FLOUT	Output	Subcarrier output (filter output)	
6 VSsa - Analog system ground 14 XOUT Output Crystal oscillator output (4.332MHz) 13 XIN Input Crystal oscillator input (external reference signal input) 9 TEST 10 MODE 15 RST PRDA Output RDS data output RDS-ID/RAM reset (active high) 16 RDCL I/O RDS clock output (master mode) / RDS read out clock input (slave mode) 17 RDS-ID/RAM reset (active high) 18 RDS-ID/RAM reset (active high) RDS clock output (master mode) / RDS read out clock input (slave mode) 19 RDS-ID/RAM reset (active high) 10 RDS clock output (master mode) / RDS read out clock input (slave mode) 10 RDS-ID/RAM reset (active high) 11 RDS-ID/RAM reset (active high) 12 VDDd - Digital system power supply (+3V)	8	CIN	Input	Subcarrier input (comparator input)	V _{SSa}
14 XOUT Output Crystal oscillator output (4.332MHz) 13 XIN Input Crystal oscillator input (external reference signal input) 14 XOUT Output Crystal oscillator input (external reference signal input) 15 RST 10 MODE 15 RST Test input Read out mode (0:master, 1:slave) RDS-ID/RAM reset (active high) 7 VSSd 2 RDDA Output RDS data output RDS data output RDS clock output (master mode) / RDS read out clock input (slave mode) 1 RDS-ID/ RADY Output RDS reliability data output (High-data with high RDS reliability) Low: data with low RDS reliability READY output (active high) 1 VDDd TODD TO	5	V _{DD} a	-	Analog system power supply (+3V)	
13 XIN Input Crystal oscillator input (external reference signal input) 9 TEST 10 MODE 15 RST Crest input Read out mode (0:master, 1:slave) RDS-ID/RAM reset (active high) 7 VSSd 2 RDDA Output RDS data output PDD RDS data output VDD RDS read out clock input (slave mode) RDS read out clock input (slave mode) 1 RDS-ID/ READY RDS reliability data output (High:data with high RDS reliability) READY output (active high) 1 VDD READY output (active high)	6	V _{SS} a	-	Analog system ground	
Test input Read out mode (0:master, 1:slave) RDS-ID/RAM reset (active high) RDS data output RDS data output RDS reliability data output READY RDS-ID/RAM reset (slave mode) RDS-ID/RAM reset (active high) RDS data output RDS data output RDS reliability data output (High data with high RDS reliability) READY output (active high) RDS reliability (High data with low RDS reliability) READY output (active high) RDS reliability (active high) RDS reliability (active high)	14	XOUT	Output	Crystal oscillator output (4.332MHz)	Vppd
Read out mode (0:master, 1:slave) RDS-ID/RAM reset (active high) RDS-ID/RAM reset (active high) RDS data output RDS data output RDS clock output (master mode) / RDS read out clock input (slave mode) RDS read out clock input (slave mode) READY READY RDS reliability data output (High:data with high RDS reliability) READY output (active high) RDS reliability) READY output (active high) RDS reliability) READY output (active high)	13	XIN	Input		XIN VSSd
RDS-ID/RAM reset (active high) RDS-ID/RAM reset (active high) RDS data output RDS data output RDS data output RDS clock output (master mode) / RDS read out clock input (slave mode) RDS read out clock input (slave mode) READY	9	TEST		Test input	
2 RDDA Output RDS data output 16 RDCL I/O RDS clock output (master mode) / RDS read out clock input (slave mode) 1 RDS-ID/ READY Output RDS reliability Low: data with low RDS reliability) READY output (active high) 1 Vond 1 Vond 1 Vond 1 Vond 1 RDS-ID/ READY Output RDS reliability (High:data output (High:data with low RDS reliability) READY output (active high)	10	MODE		Read out mode (0:master, 1:slave)	
16 RDCL I/O RDS clock output (master mode) / RDS read out clock input (slave mode) 1 RDS-ID/ READY Output (High:data output (High:data with high RDS reliability Low: data with low RDS reliability) READY output (active high) 12 VDDd - Digital system power supply (+3V)	15	RST		RDS-ID/RAM reset (active high)	/// V _{SS} d
RDS read out clock input (slave mode) 1 RDS-ID/ READY Output (High:data output (High:data with high RDS reliability Low: data with low RDS reliability) READY output (active high) 1 VDDd - Digital system power supply (+3V)	2	RDDA	Output	RDS data output	V _{DD} d → → → V _{SS} d
READY (High:data with high RDS reliability Low: data with low RDS reliability) READY output (active high) VSSd //// 12 VDDd - Digital system power supply (+3V)	16	RDCL	I/O		√ V _{DD} d → V _{SS} d
	1		Output	(High:data with high RDS reliability Low: data with low RDS reliability)	V _{SSd} ////
11 V _{SS} d - Digital system ground	12	V _{DD} d	-	Digital system power supply (+3V)	
	11	V _{SS} d	-	Digital system ground	

Input/Output Data Format

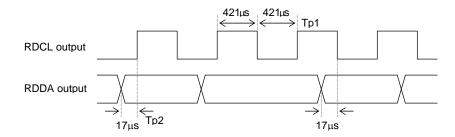
TEST	MODE	Circuit Operation Mode	RDCL Pin	RDS-ID/READY Pin
0	0	Master read out mode	Clock output	RDS-ID output
0	1	Slave read out mode	Clock input	READY output
1	0	Standby mode (crystal oscillator stopped)	-	-
1	1	IC test mode which is not available to user applications.	-	-

	RST Pin
RST = 0	Normal operation
RST = 1	RDS-ID • demodulation circuit clear + READY • memory clear (when slave mode)

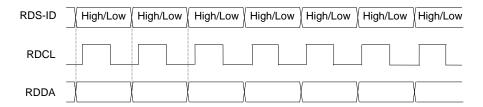
	RDS-ID/READY Pin
Master mode	RDS-ID output (Active-high)
Slave mode	READY output (Active-high)

Note: RDS-ID(READY) pin is an n-channel open-drain output, and requires an external pull-up resistor to output data.

RDCL/RDDA Output Timing in Master Mode

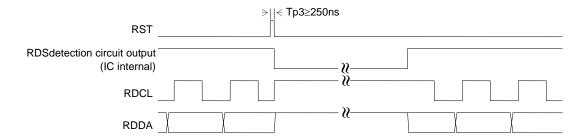


RDS-ID Output Timing



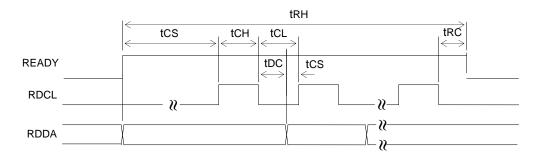
Note: RDS-ID is High: data with high RDS reliability, Low: data with low RDS reliability

RST Operation in Master Mode



Note: RDCL and RDDA outputs keep high level after input of RST until RDS detection circuit output is detected.

RDCL Operation in Slave Mode



D	0 1 1 5: 11	Die Nees	Pin Name Conditions	Ratings			
Parameter	Symbol	Pin Name		min	typ	max	unit
RDCL setup time	tCS	RDCL,RDDA		0			μS
RDCL high-level time	tCH	RDCL		0.75			μS
RDCL low-level time	tCL	RDCL		0.75			μS
Data output time	tDC	RDCL,RDDA				0.75	μS
READY output time	tRC	RDCL,READY				0.75	μS
READY high-level time	tRH	READY				107	ms

- Notes: 1. RDCL input must be started after READY signal goes high. When READY signal is low, RDCL must be low level.
 - 2. READY status must be checked after tRC time from RDCL is set low. If the READY status is high, then next read cycle can be continued. If the READY status is low, next RDCL clock input must be stopped.
 - 3. If the above condition is satisfied, RDS data (RDDA) can be read out at both rising and falling edge of RDCL.
 - 4. READY signal goes low after the last data is read out from on-chip memory. If one RDS data is stored in the memory, READY signal goes high again.
 - 5. When the reception channel is changed, a memory and READY reset must be applied using RST input. If a reset is not applied, reception data from the previous channel may remain in memory. If RST input is applied, reception data is not stored in memory until the first RDS-ID is detected, and READY output goes high after the first RDS-ID is detected. After the first RDS-ID is detected, reception data is stored even if RDS-ID is not detected.
 - 6. The readout mode may be switched between master and slave modes during readout.

 Applications must observe the following points to assure data continuity during this operation.
 - Data acquisition timing in master made
 Data must be read on the falling edge of RDCL
 - 2) Timing of the switch from master mode to slave mode

After the RDCL output goes low and the RDDA data has been acquired, the application must set MODE high immediately.

Then, the microcontroller starts output by setting the RDCL signal low.

The microcontroller RDCL output must start within 840µs (tms) after RDCL went low.

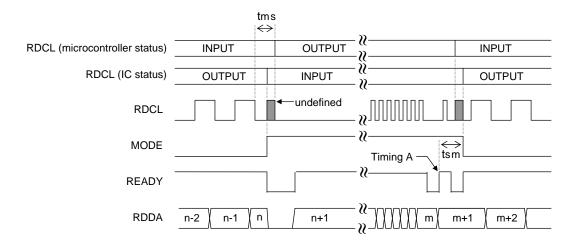
In this case, if the last data read in master mode was data item n, then data starting with item n+1 will be written to memory.

3) Timing of the switch from slave mode to master mode

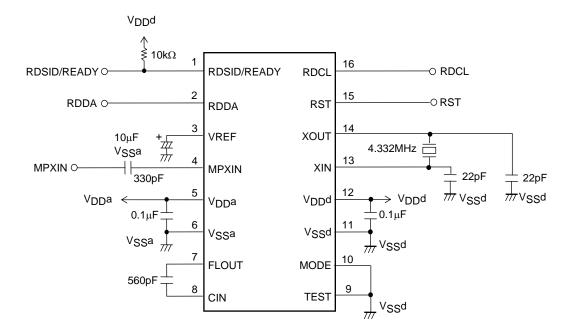
After all data has been read from memory and READY has gone high, the application must then wait until READY goes low once again the next time (timing A in the figure), immediately read out one bit of data and input the RDCL clock.

Then, at the point READY goes high, the microcontroller must terminate RDCL output and then set MODE low.

The application must switch MODE to low within 840µs (tms) after READY goes low (timing A in the figure).



Sample Application Connection Circuit (for master mode operation)



Note: If the RST pin is unused, it must be connected to ground.

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